terotest

GX5290 Series

Dynamically Controlled 200MHz High Speed Digital I/O PXI Card

The GX5290 Series are high performance, cost-effective 3U PXI dynamic digital I/O boards from Geotest, offering up to 32 TTL or LVDS input or output channels with dynamic direction control. The GX5290 Series also support deep pattern memory by offering 256 MB of on-board vector memory with dynamic per pin direction control and with test rates up to 100 MHz. The single board design supports both master and slave functionality without the use of add-on modules.

The GX5290 series includes the GX5292, with 32 channels and vector rates of 100MHz, and the GX5293 with 16 channels and vector rates of 200MHz.

Legacy ATE replacement:

When used as part of a GBATS or iTest solution and in conjunction with Geotest's LASAR linked DtifEasy software toolset, the GX529x and GX5055 cards offer a cost-effective solution for the replacement of various legacy systems, including:

- Genrad 1795,1796, 2225, 2235, 2750
- Hewlett Packard DTS-70
- Teradyne L200 and L300
- Schlumberger 730 and 790

Key Features:

- up to 32 input / output channels, dynamically configurable on a per channel basis
- 256 MB of on-board vector memory
- Supports 1.5 V, 1.8 V, 2.5 V, 3.3 V, and 5 V TTL / LVTTL interfaces
- Supports LVDS, M-LVDS, LVDM interfaces
- 100 MHz and 200MHz vector rates for GX5292 and GX5293 respectively
- Full support for LASAR simulated Go / No Go test patterns, Guided Probe and Fault Dictionary via DtifEasy software
- Channel count decreases to 16 for 200MHz vector rates of the GX5293 model
- Operates as a stand-alone card or with up to seven additional synchronous slave boards

Applications:

- Automatic Test Equipment
- Semiconductor device testing
- Displays, printers, and disk drive testing
- ASIC testing
- A/D and D/A testing
- Video acquisition / playback applications
- High speed, bi-directional bus testing / emulation
- Ideal for legacy ATE replacement of various test systems when used as part of a GBATS / iTest solution together with DtifEasy software.

Guided Probe & Fault Dictionary

The guided probe consists of 3 channels from the digital hardware - a digital probe, a momentary push button and a status indicator. The probe is compatible with both the GX529x and GX5055 digital cards and provides the probed UUT states for the guided probe sequence, and can use the fault dictionary files to reduce the time needed to locate a faulty component.

If you thought you couldn't test it.....
.....talk to us !

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